

**Search Notes**

Application/Control No.

10/535,715

Examiner

HUYEN D. LE

Applicant(s)/Patent under  
Reexamination

IWAYAMA ET AL.

Art Unit

2615

**SEARCHED**

Class	Subclass	Date	Examiner
381	87, 337, 339, 340, 341, 342	12/11/2006	HL
	343		
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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner